



FAST CMOS OCTAL TRANSPARENT LATCH

IDT74FCT2573T/AT/CT

FEATURES:

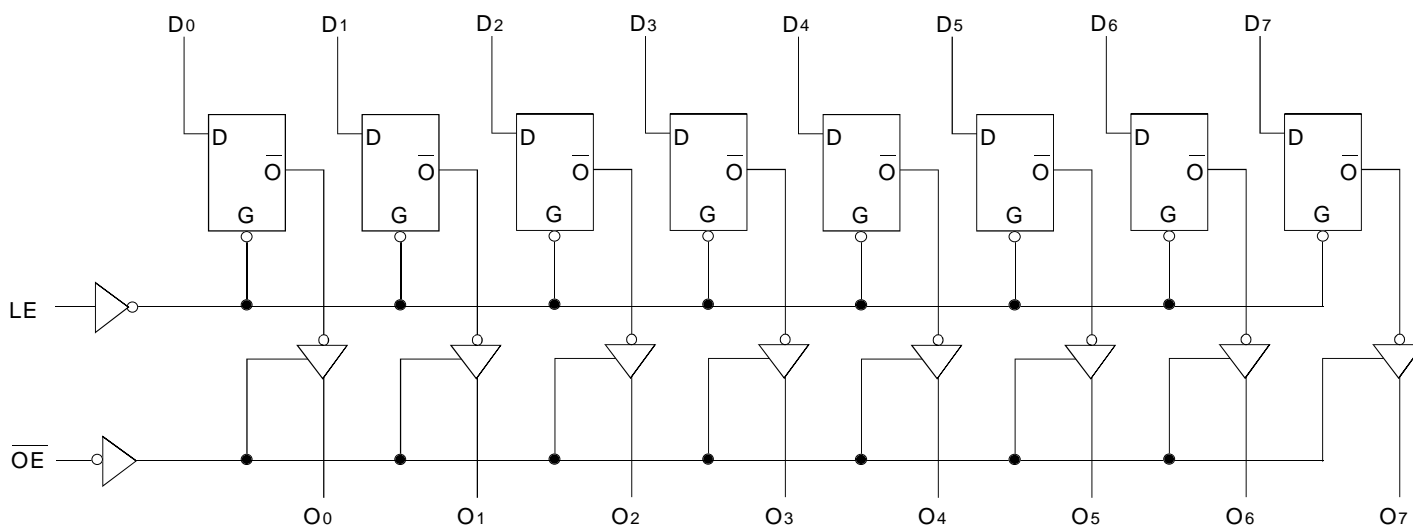
- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- CMOS power levels
- True TTL input and output compatibility
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- Meets or exceeds JEDEC standard 18 specifications
- Std., A, and C speed grades
- Resistor output (-15mA IOH, 12mA IOL)
- Reduced system switching noise
- Available in SOIC, QSOP, and TSSOP packages

DESCRIPTION:

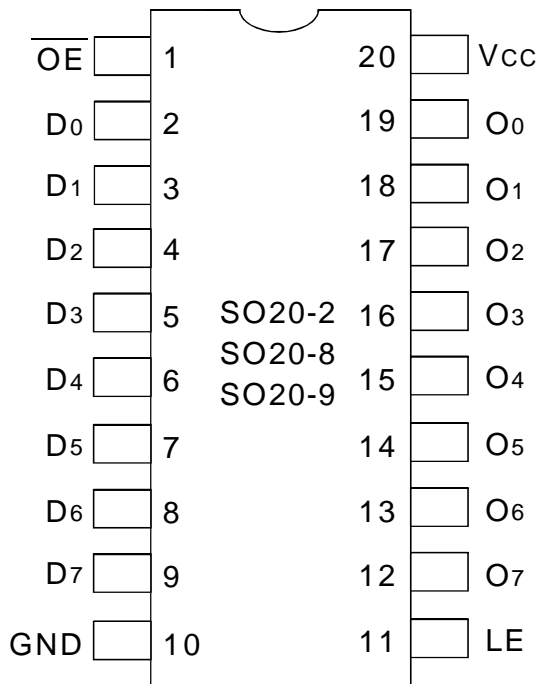
The FCT2573T is an octal transparent latch built using advanced dual metal CMOS technology. These octal latches have 3-state outputs and are intended for bus oriented applications. The flip-flops appear transparent to the data when Latch Enable (LE) is high. When LE is low, the data that meets the set-up time is latched. Data appears on the bus when the Output Enable (\overline{OE}) is low. When \overline{OE} is high, the bus output is in the high-impedance state.

The FCT2573T has balanced drive outputs with current limiting resistors. This offers low ground bounce, minimal undershoot and controlled output fall times-reducing the need for external series terminating resistors. The FCT2573T parts are plug-in replacements for FCT573T parts.

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



ABSOLUTE MAXIMUM RATINGS(1)

| Symbol | Rating | Max. | Unit |
|----------------------|--------------------------------------|------------------------------|------|
| VTERM ⁽²⁾ | Terminal Voltage with Respect to GND | -0.5 to +7 | V |
| VTERM ⁽³⁾ | Terminal Voltage with Respect to GND | -0.5 to V _{CC} +0.5 | V |
| TSTG | Storage Temperature | -65 to +150 | °C |
| I _{OUT} | DC Output Current | -60 to +120 | mA |

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NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V_{CC} by +0.5V unless otherwise noted.
- Inputs and V_{CC} terminals only.
- Outputs and I/O terminals only.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

| Symbol | Parameter ⁽¹⁾ | Conditions | Typ. | Max. | Unit |
|------------------|--------------------------|-----------------------|------|------|------|
| C _{IN} | Input Capacitance | V _{IN} = 0V | 6 | 10 | pF |
| C _{OUT} | Output Capacitance | V _{OUT} = 0V | 8 | 12 | pF |

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NOTE:

- This parameter is measured at characterization but not tested.

PIN DESCRIPTION

| Pin Names | Description |
|-----------------|----------------------------------|
| D _N | Data Inputs |
| LE | Latch Enable Input (Active HIGH) |
| \overline{OE} | Output Enable Input (Active LOW) |
| O _N | 3-State Outputs |

FUNCTION TABLE (1)

| Inputs | | | Outputs |
|----------------|----|-----------------|----------------|
| D _N | LE | \overline{OE} | O _N |
| H | H | L | L |
| L | H | L | H |
| X | X | H | Z |

NOTE:

- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High-Impedance

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Industrial: $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = 5.0\text{V} \pm 5\%$

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|-----------|---|--|---------------------|------|---------------------|---------|---------------|
| V_{IH} | Input HIGH Level | Guaranteed Logic HIGH Level | | 2 | — | — | V |
| V_{IL} | Input LOW Level | Guaranteed Logic LOW Level | | — | — | 0.8 | V |
| I_{IH} | Input HIGH Current ⁽⁴⁾ | $V_{CC} = \text{Max.}$ | $V_I = 2.7\text{V}$ | — | — | ± 1 | μA |
| I_{IL} | Input LOW Current ⁽⁴⁾ | | $V_I = 0.5\text{V}$ | — | — | ± 1 | μA |
| I_{OZH} | High Impedance Output Current (3-State output pins) ⁽⁴⁾ | $V_{CC} = \text{Max.}$ | $V_O = 2.7\text{V}$ | — | — | ± 1 | μA |
| I_{OZL} | | | $V_O = 0.5\text{V}$ | — | — | ± 1 | |
| I_I | Input HIGH Current | $V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$ | | — | — | ± 1 | μA |
| V_{IK} | Clamp Diode Voltage | $V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$ | | — | -0.7 | -1.2 | V |
| V_H | Input Hysteresis | — | | — | 200 | — | mV |
| I_{CC} | Quiescent Power Supply Current | $V_{CC} = \text{Max.}, V_{IN} = \text{GND or } V_{CC}$ | | — | 0.01 | 1 | μA |

OUTPUT DRIVE CHARACTERISTICS

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|-----------|---------------------|---|-------------------------|------|---------------------|------|---------------|
| I_{ODL} | Input LOW Current | $V_{CC} = 0\text{V}, V_{IN} = V_{IH} \text{ or } V_{IL}, V_{OUT} = 1.5\text{V}^{(3)}$ | | 16 | 48 | — | μA |
| I_{ODH} | Input HIGH Current | $V_{CC} = 0\text{V}, V_{IN} = V_{IH} \text{ or } V_{IL}, V_{OUT} = 1.5\text{V}^{(3)}$ | | -16 | -48 | — | μA |
| V_{OH} | Output HIGH Voltage | $V_{CC} = \text{Min.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$ | $I_{OH} = -15\text{mA}$ | 2.4 | 3.3 | — | V |
| V_{OL} | Output LOW Voltage | $V_{CC} = \text{Min.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$ | $I_{OL} = 12\text{mA}$ | — | 0.3 | 0.5 | V |

NOTES:

1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at $V_{CC} = 5.0\text{V}$, $+25^{\circ}\text{C}$ ambient and maximum loading.
3. Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
4. The test limit for this parameter is $\pm 5\mu\text{A}$ at $T_A = -55^{\circ}\text{C}$.
5. This parameter is guaranteed but not tested.

POWER SUPPLY CHARACTERISTICS

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|-----------------|---|---|--|------|---------------------|---------------------|------------|
| ΔI_{CC} | Quiescent Power Supply Current TTL Inputs HIGH | $V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$ | | — | 0.5 | 2 | mA |
| I_{CCD} | Dynamic Power Supply Current ⁽⁴⁾ | $V_{CC} = \text{Max.}$ Outputs Open $\overline{OE} = \text{GND}$ One Input Toggling 50% Duty Cycle | $V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$ | — | 0.06 | 0.12 | mA/ MHz |
| I_C | Total Power Supply Current ⁽⁶⁾ | $V_{CC} = \text{Max.}$ Outputs Open $f_i = 10\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ $LE = V_{CC}$ One Bit Toggling | $V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$ | — | 0.6 | 2.2 | mA |
| | | | $V_{IN} = 3.4$ $V_{IN} = \text{GND}$ | — | 0.9 | 3.2 | |
| | | $V_{CC} = \text{Max.}$ Outputs Open $f_i = 2.5\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ $LE = V_{CC}$ Eight Bits Toggling | $V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$ | — | 1.2 | 3.4 ⁽⁵⁾ | |
| | | | $V_{IN} = 3.4$ $V_{IN} = \text{GND}$ | — | 3.2 | 11.4 ⁽⁵⁾ | |

NOTES:

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient.
- Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND .
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$

$$I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + f_i N_i)$$

I_{CC} = Quiescent Current

ΔI_{CC} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)

f_i = Input Frequency

N_i = Number of Inputs at f_i

All currents are in milliamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

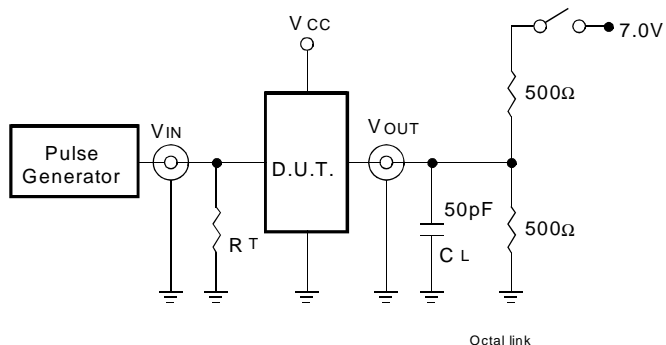
| Symbol | Parameter | Condition ⁽¹⁾ | FCT2573T | | FCT2573AT | | FCT2573CT | | Unit |
|--------------------------------------|---|--|---------------------|-----|---------------------|------|---------------------|------|------|
| | | | Min. ⁽²⁾ | Max | Min. ⁽²⁾ | Max. | Min. ⁽²⁾ | Max. | |
| t _{PLH} t _{PHL} | Propagation Delay D _N to O _N | C _L = 50pF R _L = 500Ω | 1.5 | 8 | 1.5 | 5.2 | 1.5 | 4.2 | ns |
| t _{PLH} t _{PHL} | Propagation Delay LE to O _N | | 2 | 13 | 2 | 8.5 | 2 | 5.5 | ns |
| t _{PZH} t _{PZL} | Output Enable Time | | 1.5 | 12 | 1.5 | 6.5 | 1.5 | 5.5 | ns |
| t _{PHZ} t _{PLZ} | Output Disable Time | | 1.5 | 7.5 | 1.5 | 5.5 | 1.5 | 5 | ns |
| t _{SU} | Set-up Time HIGH or LOW, D _N to LE | | 2 | — | 2 | — | 2 | — | ns |
| t _H | Hold Time HIGH or LOW, D _N to LE | | 1.5 | — | 1.5 | — | 1.5 | — | ns |
| t _w | LE Pulse Width HIGH ⁽³⁾ | | 6 | — | 5 | — | 5 | — | ns |

NOTES:

1. See test circuit and wave forms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. This parameter is guaranteed but not tested.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

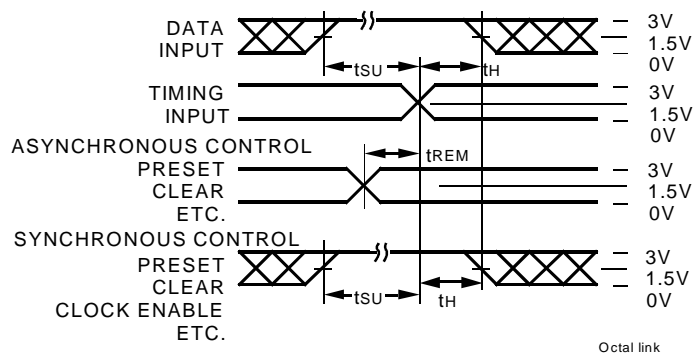
| Test | Switch |
|-----------------|--------|
| Open Drain | Closed |
| Disable Low | |
| Enable Low | |
| All Other Tests | Open |

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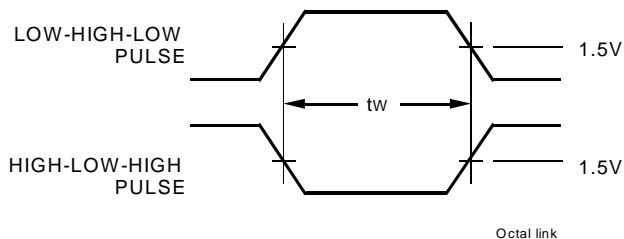
DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.
RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

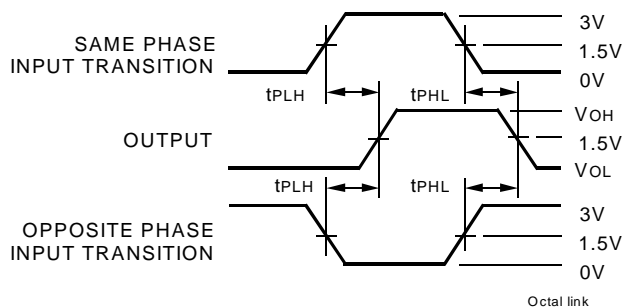
SET-UP, HOLD, AND RELEASE TIMES



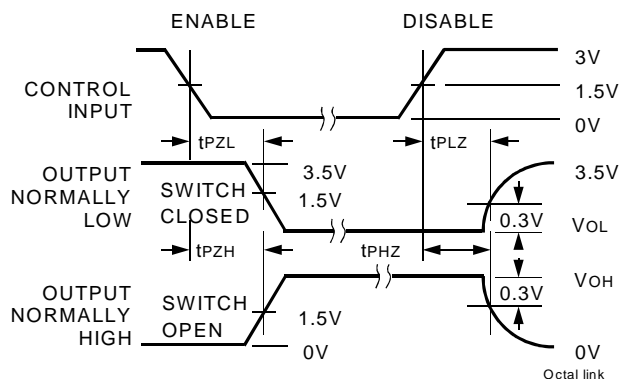
PULSE WIDTH



PROPAGATION DELAY



ENABLE AND DISABLE TIMES

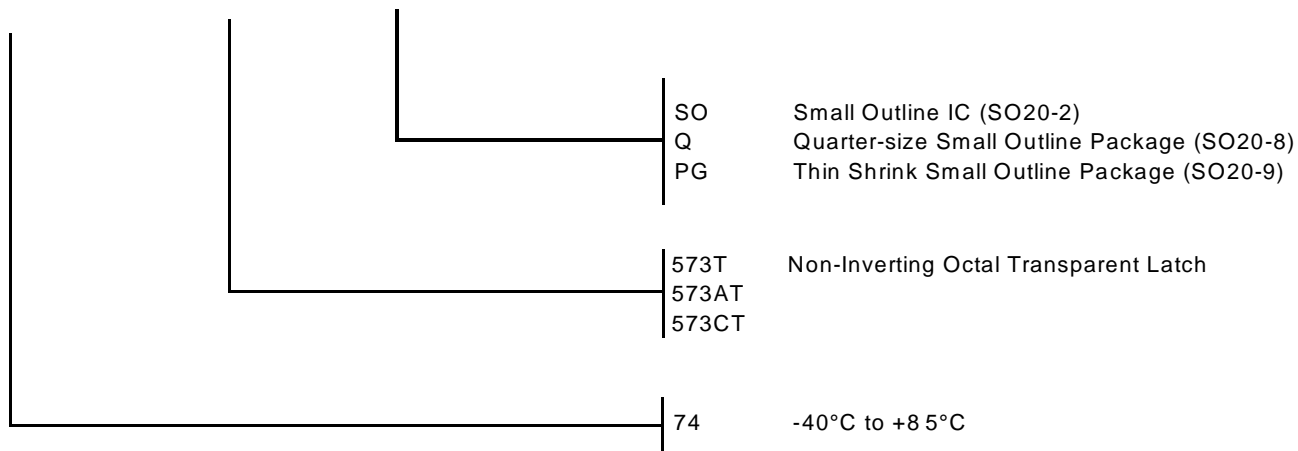


NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$

ORDERING INFORMATION

IDT XX FCT XXXX X
Temp. Range Device Type Package



CORPORATE HEADQUARTERS
2975 Stender Way
Santa Clara, CA 95054

for SALES:
800-345-7015 or 408-727-6116
fax: 408-492-8674
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